

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10579418	STEK ET AL.
	Examiner	Art Unit
	Huynh, Phuong	2857

SEARCHED

Class	Subclass	Date	Examiner
702	150	04/17/2007	PH
73	865.9	04/18/2007	PH
324	207.2; 207.25	04/18/2007	PH
UPDATED	ABOVE	08/10/07	PH
702	109-113, 116, 142-147, 151-153, 163	08/10/2007	PH
324	76.12, 76.14	08/10/2007	PH
UPDATED	ABOVE	08/12/2007	PH
341	8,115	08/12/2007	PH
324	207.12, 207.14; 76.13	08/12/2007	PH

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with Primary Examiner Blane Jackson (AU 2618); no search in 455	04/18/2007	PH
Consulted with Primary Examiner Thomas Noland : 73/865.9; 324/207.2,207.25	04/18/2007	PH
702/150; 73/865.9; 324/207.2, 207.25 with text	04/18/2007	PH
Assignment data (eDan)	04/18/2007	PH
702/109-113, 116, 142-147, 150-153, 163; 324/207.2; 207.25,76.12,76.14; 73/865.9 with text	08/10/2007	PH
702/109-113, 116, 142-147, 150-153, 163; 324/207.2; 207.12, 207.14, 207.25,76.12,76.13,76.14; 73/865.9; 341/8, 15 with text	8/12/2007	PH

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
702	112,113,145	08/12/2007	PH
73	865.9	8/12/2007	PH
341	8,115	8/12/2007	PH
324	207.12; 76.13	8/12/2007	PH